

Novel High-k Application Workshop

March 14th, 2016

Time	Presenter	Institute	Title of Presentation
9:00	T. Mikolajick/U. Schroeder	Namlab	Welcome
High-k Devices <i>chair: U. Schroeder</i>			
1 9:15	K. Cherkaoui/P. Hurley	Tyndall National Institute, Cork IE	High-k on III/V semiconductors
2 9:35	J. Roberts/P. Chalker	Univ. Liverpool, GB	Dielectrics for AlGaIn/GaN MISHEMT power electronics
3 9:55	J. Schubert	FZ Juelich, D	Rare earth oxides on GaN
4 10:15	N. Szabo	Namlab Dresden, D	ALD Al ₂ O ₃ as a high-k dielectric material for future GaN power devices
5 10:30	M. Drescher	Fraunhofer IPMS-CNT, Dresden, D	Deciphering Reliability in High-K Metal Gate Technology
Coffee break: 10:50 - 11:20h			
Novel Devices <i>chair: T. Mikolajick</i>			
6 11:20	E. Erben	GlobalFoundries Dresden, D	Workfunction tuning and gate stack for 22nm FD-SOI
7 11:40	F. Winkler/J. Bartha	TU Dresden, IHM, D	Novel vertical TSV field effect transistor using ALD high-k gate dielectrics
8 12:00	A. Thomas	IFW Dresden, D	ALD deposited HfO ₂ -based magnetic tunnel junctions
9 12:20	M. Godlewski	Acad. of Sc. Warsaw, PL	High-k oxides by ALD - from applications in electronics to biology and medicine
Lunch - Alte Mensa (Helmholtz Strasse): 12:40 - 14:00h			
Memory Devices <i>chair: U. Schroeder</i>			
10 14:00	J. Van Houdt	IMEC Leuven, B	High k in memory devices
Ferroelectric devices			
11 14:30	M.H. Park/ CS Hwang	Seoul National University, Seoul, KR	Current understanding of ferroelectricity and field-induced-ferroelectricity in (Hf,Zr)Q films based on first order phase transition theory
12 14:50	S. Starschich	RWTH Aachen IWE, D	Rare earth oxide doped ferroelectric HfO ₂ layers
13 15:10	R. Materlik/A. Kersch	UAS Munich, D	Ferroelectricity in HfZrO: A Computational Investigation
14 15:30	T. Tromm/J. Schubert	FZ Juelich, D	PLD grown ferroelectric HfO ₂
15 15:50	H. Mulaosmanovic	Namlab Dresden, D	Single domain switching in ferroelectric HfO ₂
Coffee break: 16:05 - 16:30h			
RRAM <i>chair: S. Slesazek</i>			
16 16:30	E. Jalaguier	CEA-LETI, Grenoble, F	Reliability improvement thanks to Al ₂ O ₃ in HfO ₂ based RRAM
17 16:50	K. Fröhlich	Acad. of Sc., Bratislava, SK	Memory application of HfO ₂ -based resistive switching structures
18 17:10	S. Spiga	CNR-IMM, Agrate Brianza, I	HfO ₂ -based memristive devices for RRAM and neuromorphic applications
19 17:30	C. Wenger	IHP Frankfurt/Oder, D	Switching Performance of HfO ₂ -based Resistive Memory Arrays
20 17:50	U. Böttger	RWTH Aachen, D	Resistive switching oxides
21 18:10	H. Wylezich	Namlab Dresden, D	Operating resistive switching cells in passive cross-bar arrays
18:25	End		
Location:	Goerges Bau, TU Dresden, Helmholtzstrasse		
19:30	Workshop Dinner	Brauhaus Waldschlösschen	co-sponsored by Oxford Instruments, Pegasus, and FAB Support

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March 15th, 2015

Solar 1 <i>chair: I. Dirnstorfer</i>			
1 9:00	F. Roozeboom	TU Eindhoven/TNO, NL	Spatial Atomic Layer Deposition of Zn(O,S) buffer layers for CIGS solar cells
2 9:20	M. Szindler	Silesian Univ. of Technology, Gliwice, PL	Silicon solar cells with Al ₂ O ₃ antireflection coating deposited by ALD
3 9:40	M. Sowińska	BTU Cottbus - Senftenberg, D	ALD growth of Al ₂ O ₃ on CH ₃ NH ₃ PbI ₃ : spectroscopic investigation for perovskite solar cells
4 10:00	P. Jordan	Namlab Dresden, D	Conductive Al ₂ O ₃ based passivation layers
5 10:15	F. Kersten/J. Heitmann	TUBA Freiberg	Degradation of Multi PERC cells
6 10:30	M. Godlewski	Acad. of Sc. Warsaw, PL	Transparent 3D electrodes for solar cell applications
Coffee break: 10:50 - 11:20h			
Solar 2/TCOs <i>chair: I. Dirnstorfer</i>			
7 11:20	R. Klenk	Helmholtz-Zentrum Berlin, D	ALD processes for junction formation in CIGS solar cells
8 11:40	T. Törndahl	Uppsala University, S	High performing hydrogen doped In ₂ O ₃ for CIGS solar cells
9 12:00	H. Knoops	Oxford Instruments, NL	Advances in transparent conductive oxides by ALD: Doped ZnO, In ₂ O ₃ and related materials
10 12:20	R. Zazpe	University of Pardubice, CZ	Antireflection In ₂ O ₃ coating of self-organized TiO ₂ nanotube layers
11 12:40	S. Taeger	OSRAM, D	Requirements for TCOs in 2D and 3D commercial LEDs
12 13:00	R. Puruunen	VTT Technical Research Centre of Finland	High-k thin films in 3-D structures: metrology with microscopic lateral high-aspect-ratio structures
Lunch - Alte Mensa (Helmholtz Strasse): 13:20 - 14:15h			
Atomic Layer Etching (ALE) <i>chair: J. Sundqvist</i>			
13 14:15	V. Sessi/T. Mikolajick	TU Dresden, IHM, D	High-k materials on Nanowire Devices (Device talk shifted from Monday)
12 14:30	F. Roozeboom	TU Eindhoven/TNO, NL	Spatial Atomic Layer Etching
13 14:50	M. Junige	TU Dresden, D	Chemical path to ALE
14 15:10	D. Suyatin	Lund University, S	Evaluation of ALE for semiconductor nanowire devices
15 15:30	H. Knoops	Oxford Instruments, NL / TU Eindhoven, NL	Atomic Layer Etching: What Can We Learn from Atomic Layer Deposition?
Location:	Goerges Bau, TU Dresden, Helmholtzstrasse		

Namlab / TU Dresden IHM Tour: 16:00h

Poster	Room 229 Monday and Tuesday during coffee breaks		
1	E. Langenberg	Universidad de Zaragoza, ES	Dielectric characterization of (Sr _{1-x} Ba _x)MnO ₃ epitaxial thin films in the perovskite phase
2	K. Henkel	BTU Cottbus - Senftenberg, D	Plasma-enhanced atomic layer deposition of titanium oxynitrides films: A comparative spectroscopic and electrical study
3	C. Das	BTU Cottbus - Senftenberg, D	Spectroscopic study of ALD TiO ₂ on Si